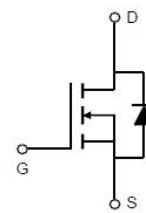
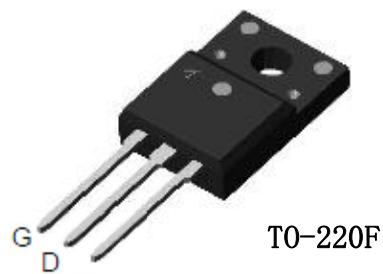


## 500V N-Channel MOSFET

### Features

- $V_{DSS}=500V$     $I_D=18A$
- $R_{DS(ON)}=0.34\Omega(\text{max.}) @ V_{GS}=10V$
- Low On-Resistance
- Excellent CdV/dt effect decline
- Super Low Gate Charge
- 100% EAS Guaranteed
- Fast switching speed

### PIN DESCRIPTION



### Applications

- Switch Mode Power Supply (SMPS)
- Uninterruptible Power Supply (UPS)
- Power Factor Correction (PFC)

Part Number	Package	Marking	ROHS Status	Packing
SI18N50AF	TO-220F	SI18N50AF	ROHS	Box(Tube)

### Absolute Maximum Ratings ( $T_c=25^\circ C$ unless otherwise noted)

Symbol	Parameter	Value	Unit
$V_{DS}$	Drain-Source Voltage	500	V
$V_{GS}$	Gate-Source Voltage	$\pm 30$	V
$I_D$	Continuous Drain Current	18	A
$I_{DM}$	Pulsed Drain Current	76	A
$I_{AR}$	Avalanche Current	19	A
$E_{AS}$	Single Pulse Avalanche Energy	945	mJ
$T_J, T_{stg}$	Operating Junction and Storage Temperature Range	-55 to 150	°C
$P_D$	Total Power Dissipation	239	W

### THERMAL RESISTANCE RATINGS

Symbol	Parameter	Value	Unit
$R_{\theta JA}$	Maximum Junction-to-Ambient	40	°C/W
$R_{\theta JC}$	Maximum Junction-to-Case	0.52	

### Electrical Characteristics (TJ=25°C unless otherwise Ratings )

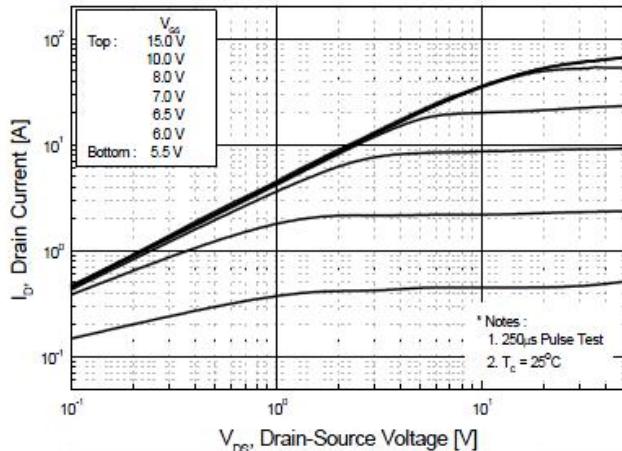
Symbol	Parameter	Test Conditions	Min.	TYP.	Max.	Unit
<b>Static Characteristics</b>						
B <sub>VDS</sub>	Drain-source breakdown voltage	V <sub>GS</sub> =0V,I <sub>DS</sub> = 250uA	500	-	-	V
V <sub>GS(th)</sub>	Gate threshold voltage	V <sub>DS</sub> =V <sub>GS</sub> ,I <sub>DS</sub> =250uA	3	-	4	V
I <sub>DSS</sub>	Drain-Source Leakage Current	V <sub>DS</sub> =500V,V <sub>GS</sub> =0V	-	-	1	uA
I <sub>GSS</sub>	Gate-source leakage current	V <sub>DS</sub> =0V,V <sub>GS</sub> =±30V	-	-	±100	nA
R <sub>DS(on)</sub>	Drain-source on-state resistance	V <sub>GS</sub> =10V,I <sub>D</sub> =9A	-	-	0.34	Ω
<b>Dynamic Characteristic</b>						
Q <sub>g</sub>	Total Gate Charge	V <sub>GS</sub> =10V,V <sub>DD</sub> =400V I <sub>D</sub> =18A	-	45.5	-	nC
Q <sub>gs</sub>	Gate-Source Charge		-	15.8	-	nC
Q <sub>gd</sub>	Gate-Drain Charge		-	21.6	-	nC
T <sub>d(on)</sub>	Turn-on delay time	I <sub>D</sub> =18A,V <sub>DD</sub> =250V, R <sub>G</sub> =25Ω	-	55	-	nS
T <sub>r</sub>	Rise time		-	165	-	nS
T <sub>d(off)</sub>	Turn-off delay time		-	95	-	nS
T <sub>f</sub>	Fall time		-	90	-	nS
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> =0V,V <sub>DS</sub> =25V f=1.0MHz	-	2200	-	pF
C <sub>oss</sub>	Output Capacitance		-	330	-	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		-	25	-	pF
<b>Source-Drain Diode</b>						
V <sub>SD</sub>	Diode Forward Voltage	V <sub>GS</sub> =0V,I <sub>SD</sub> =18A	-	-	1.4	V
I <sub>SM</sub>	Pulsed Source Current	V <sub>G</sub> =V <sub>D</sub> =0V,T <sub>C</sub> =25°C	-	-	76	A
I <sub>s</sub>	Continuous Source Current		-	-	18	A
T <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> =0V,I <sub>s</sub> =18A, dI/dt=100A /μs	-	500	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge		-	5.4	-	uC

**Notes:**

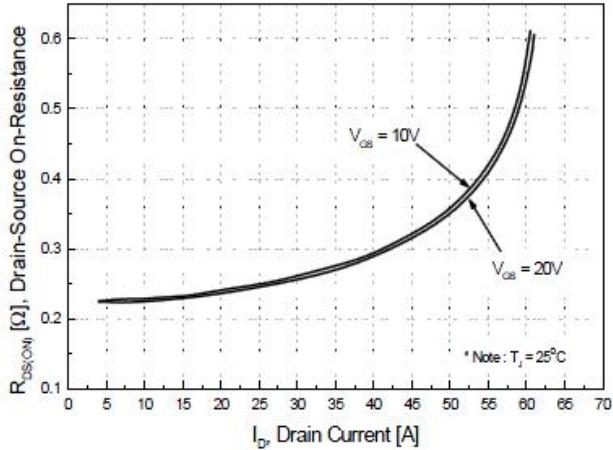
1. Repetitive Rating: Pulse width limited by maximum junction temperature.
2. Pulse Test: Pulse width ≤ 300μs, Duty Cycle ≤ 2% .

## Typical Performance Characteristics

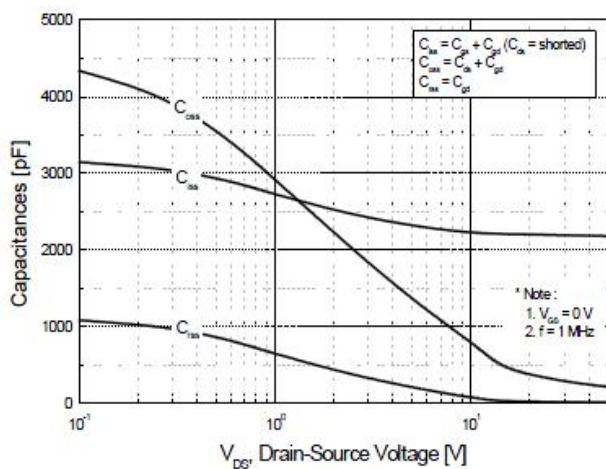
**Figure 1. On-Region Characteristics**



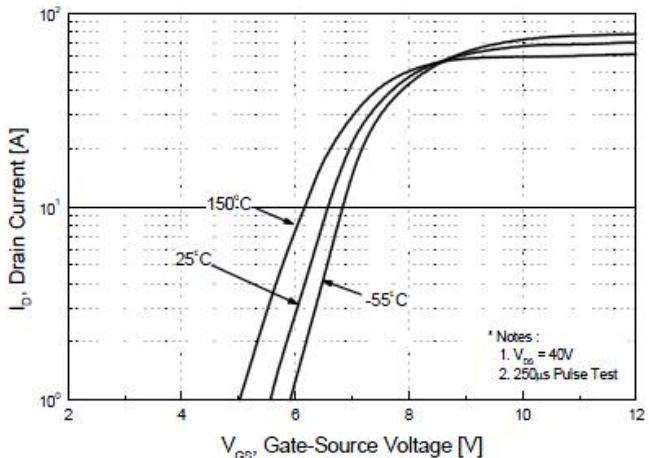
**Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage**



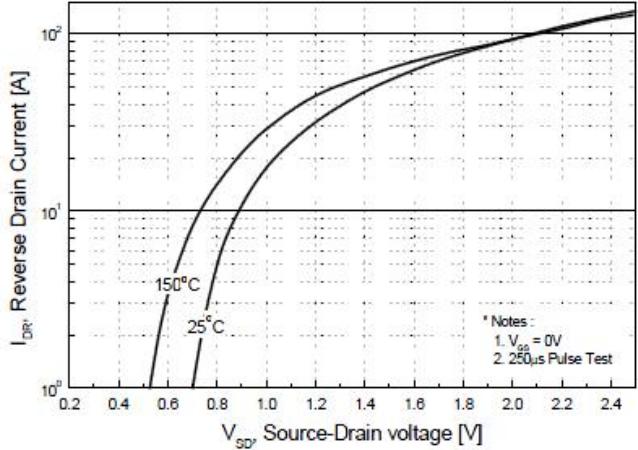
**Figure 5. Capacitance Characteristics**



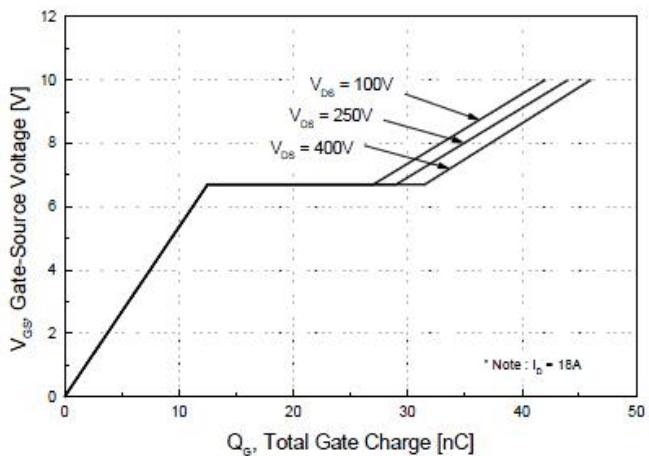
**Figure 2. Transfer Characteristics**



**Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature**

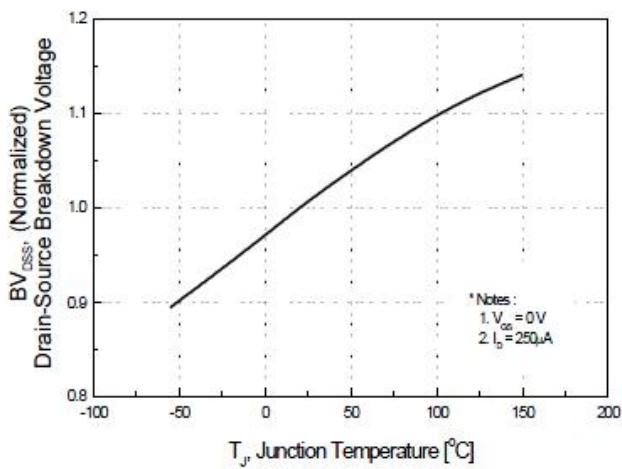


**Figure 6. Gate Charge Characteristics**

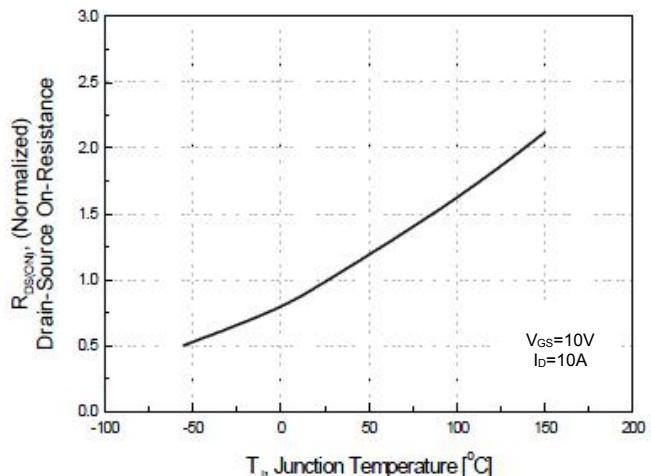


## ■ Typical Performance Characteristics (Cont.)

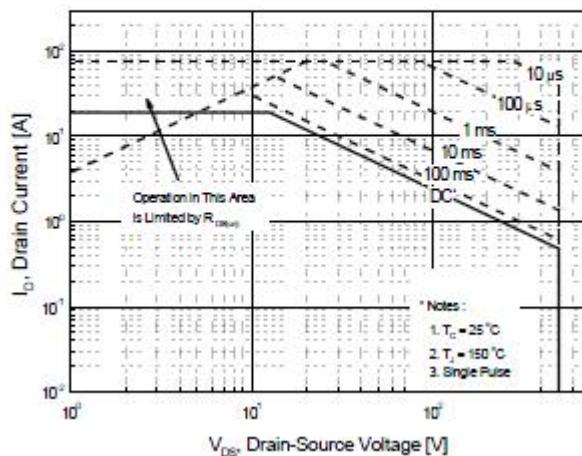
**Figure 7. Breakdown Voltage Variation vs. Temperature**



**Figure 8. On-Resistance Variation vs. Temperature**



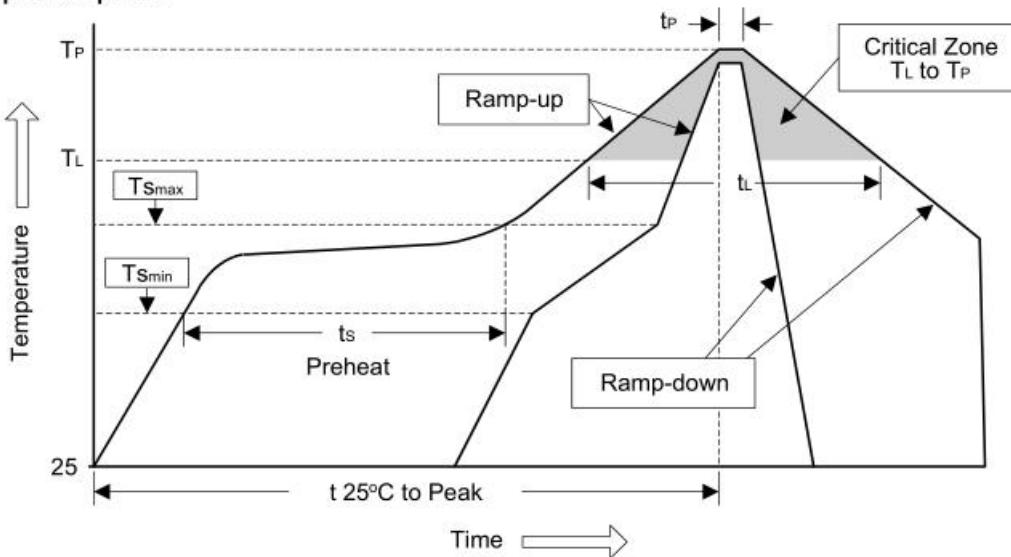
**Figure 9. Maximum Safe Operating Area**



## Soldering Methods for Products

Profile Feature	Sn-Pb Eutectic Assembly	Pb-Free Assembly
Average ramp-up rate(TL to TP)	<3°C/sec	<3°C/sec
Preheat	-	-
-Temperature Min(Ts min)	100°C	150°C
-Temperature Max(Ts max)	150°C	200°C
-Time(min to max)(ts)	60 to 120 sec	60 to 180 sec
Ts max to TL	<3°C/sec	<3°C/sec
- ramp-up rate		
Time maintained above:		
-Temperature(TL)	183°C	217°C
-Time(TL)	60 to 150 sec	60 to 150 sec
Peak Temperature(TP)	240°C+0/-5°C	250°C+0/-5°C
Time within 5°C of actual Peak Temperature	10 to 30 sec	20 to 40 sec
Ramp-down Rate	<6°C/sec	<6°C/sec
Time 25 °C to Peak Temperature	<6 minutes	<8 minutes

Figure 1: Temperature profile

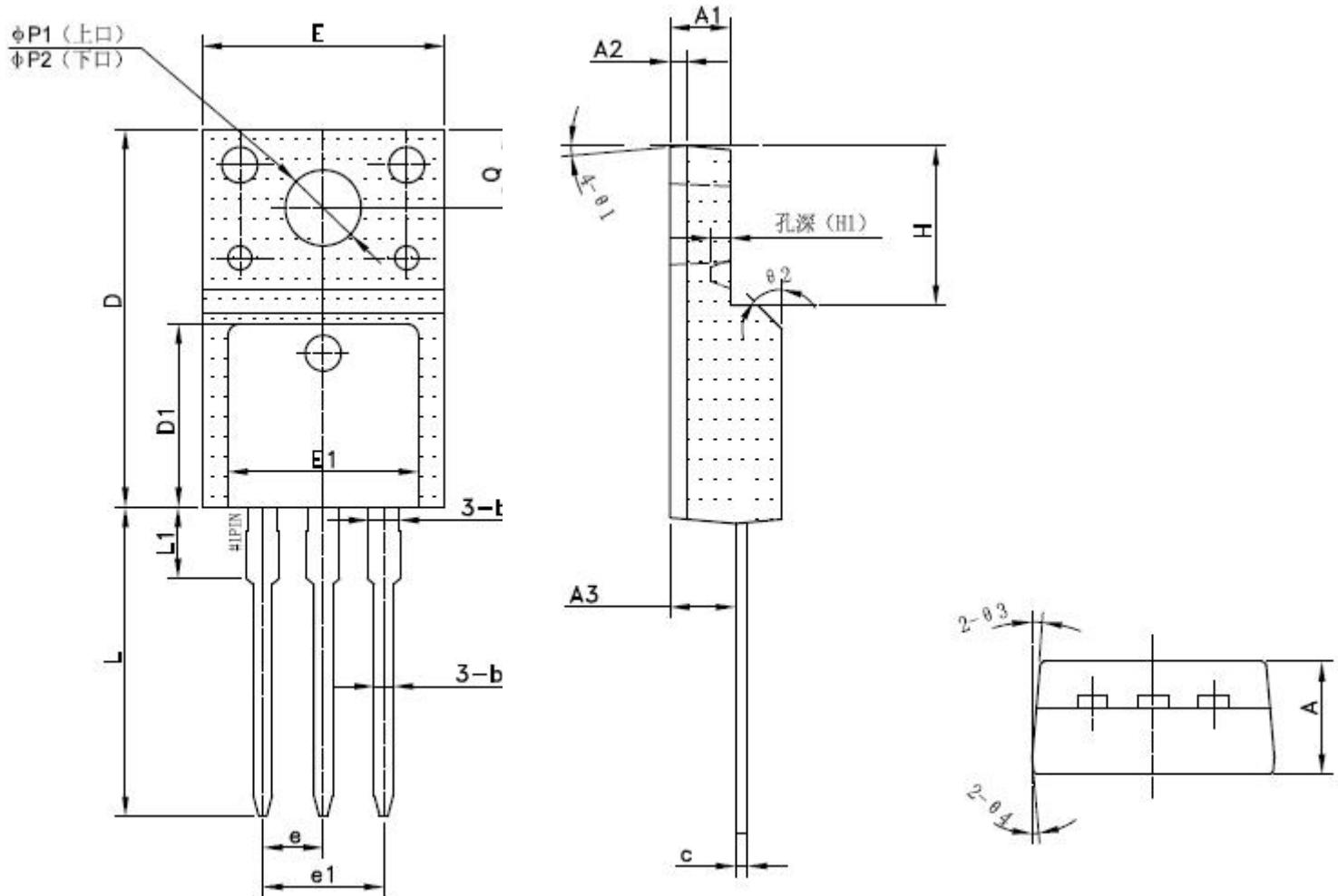


**Note :**

1. Storage environment: Temperature=10°C to 35@Humidity=45%±15%
- 2.Reflow soldering of surface-mount devices
- 3.Flow(wave) soldering(solder dipping)

Products	Peak Temperature	Dipping Time
Pb devices	245°C±5°C	5sec±1sec
Pb-free devices	250°C+0/-5°C	5sec±1sec

## Package Outline



Millimeter(mm)					
Symbol	Min	Max	Symbol	Min	Max
A	4.50	4.90	E	9.96	10.36
A1	2.44	2.64	E1	8.00TYP	
A2	0.60	0.80	e	2.54TYP	
A3	2.56	2.96	e1	5.08TYP	
b	0.70	0.95	H	6.50	6.90
b1	1.28TYP		L	12.48	13.20
c	0.45	0.65	L1	2.93TYP	
D	15.67	16.07	P1	2.98	3.38
D1	7.70TYP		P2	3.20.	3.60

## ■ Important Notice

Si-Trend reserves the right to change all product、product specifications and data without prior notice ; Our customer Please confirm to place an order confirmation before make the integrity of information complete and up-to-date 。

Any semiconductor under specific conditions are possible to certain failure or malfunction rate ; Customers are responsible in the use of Si-Trend products to system design and manufacturing in compliance with safety standards and adopting safety measures , To avoid the potential risk of failure may cause the personal safety and property loss 。

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## ■ Modify record

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